

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/485,146	HIRAIWA ET AL.	
Examiner	Art Unit	
John M. Frink	2142	

SEARCHED					
Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
inventor search	9/20/2007	JMF	
text + date	9/20/2007	JMF	
assignee + text	9/20/2007	JMF	
subclass + text	9/20/2007	JMF	